

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HIRAKATA ET AL.	
		Examiner James A. Dudek	Art Unit 2871	Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,644,370 A	07-1997	Miyawaki et al.	349/43
*	B	US-6,091,466 A	07-2000	Kim et al.	349/43
*	C	US-6,100,954 A	08-2000	Kim et al.	349/138
*	D	US-6,181,398 B1	01-2001	Libsch et al.	349/113
*	E	US-6,356,318 B1	03-2002	Kawahata, Ken	349/38
*	F	US-6,392,722 B1	05-2002	Sekime et al.	349/47
*	G	US-6,400,426 B1	06-2002	Yamazaki et al.	349/43
*	H	US-6,577,372 B2	06-2003	Zhang et al.	349/152
*	I	US-6,683,668 B2	01-2004	Moon et al.	349/138
*	J	US-2004/0046915 A1	03-2004	Takeda et al.	349/129
*	K	US-6,900,869 B1	05-2005	Lee et al.	349/129
*	L	US-6,897,929 B2	05-2005	Takeda et al.	349/129
*	M	US-6,927,824 B1	08-2005	Takeda et al.	349/129

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HIRAKATA ET AL.	
		Examiner James A. Dudek	Art Unit 2871	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0002144 A1	05-2001	Yamazaki, Shunpei	349/44
*	B	US-2001/0035919 A1	11-2001	Zhang, Hongyong	349/44
*	C	US-2002/0191124 A1	12-2002	Nakata, Shinichi	349/43
*	D	US-6,515,720 B1	02-2003	Iizuka et al.	349/39
*	E	US-6,549,259 B2	04-2003	Sato et al.	349/153
*	F	US-6,552,758 B1	04-2003	Koyama, Jun	349/43
*	G	US-2003/0210358 A1	11-2003	Zhang et al.	349/43
*	H	US-2004/0012725 A1	01-2004	Tomioka et al.	349/43
*	I	US-2004/0051100 A1	03-2004	Yamazaki et al.	257/059
*	J	US-2004/0075782 A1	04-2004	Ha et al.	349/043
*	K	US-6,721,024 B1	04-2004	Kishimoto et al.	349/123
*	L	US-2005/0041167 A1	02-2005	Sugimoto et al.	349/043
*	M	US-2005/0237442 A1	10-2005	Yamazaki et al.	349/043

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HIRAKATA ET AL.	
		Examiner James A. Dudek	Art Unit 2871	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,926,235 A	07-1999	Han et al.	349/43
*	B	US-6,633,356 B1	10-2003	Kataoka et al.	349/129
*	C	US-2003/0197179 A1	10-2003	Yamazaki et al.	257/59
*	D	US-RE38,288 E	10-2003	Yamada et al.	349/156
*	E	US-6,661,488 B1	12-2003	Takeda et al.	349/117
*	F	US-6,670,635 B1	12-2003	Yamazaki et al.	257/59
*	G	US-2006/0091387 A1	05-2006	Yamazaki, Shunpei	257/059
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.